

Notice of References Cited	Application/Control No. 10/538,456		Applicant(s)/Patent Under Reexamination OMATHUNA, PADRAIG	
	Examiner KALPIT PARIKH		Art Unit 2187	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Introduction to JTAG Boundary Scan, January 1997, Sun Microelectronics, Pages 1-9.			
	V				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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